Four-quadrant triac, enhanced noise immunity Rev. 01 — 19 May 2008

Product data sheet

1. Product profile

1.1 General description

Passivated sensitive gate triac in a SOT54A (wide pitch) plastic package

1.2 Features

- Sensitive gate
- Direct interfacing to logic level ICs
- Enhanced immunity to voltage transients and noise
- Gate triggering in four quadrants
- Direct interfacing to low power gate drive circuits
- High blocking voltage to 800 V

1.3 Applications

- Home appliances
- Low power AC fan speed controllers
- Low power motor control
- Low power loads in industrial process control

1.4 Quick reference data

- $V_{DRM} \le 800 \text{ V}$
- $I_{TSM} \le 12.5 \text{ A (t = 20 ms)}$
- $I_{T(RMS)} \le 1 A$

- $I_{GT} \le 5 \text{ mA}$
- $I_{GT} \le 7 \text{ mA } (T2-G+)$

Pinning information

Table 1 Pinning

Pin	Description	Simplified outline	Graphic symbol
1	main terminal 2 (T2)		
2	gate (G)		T2—T1
3	main terminal 1 (T1)		`G sym051
		SOT54A	



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3. Ordering information

Table 2. Ordering information

Type number	Package					
	Name	Description	Version			
OT407	-	plastic single-ended leaded (through hole) package; 3 leads (wide pitch)	SOT54A			

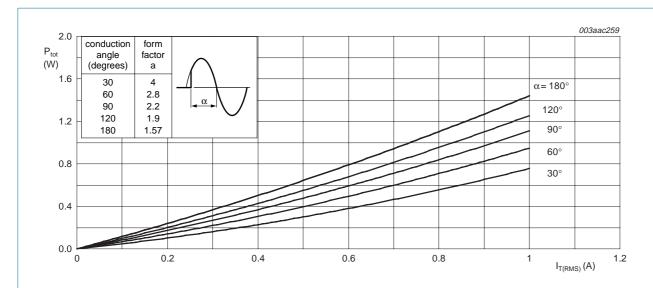
4. Limiting values

Table 3. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

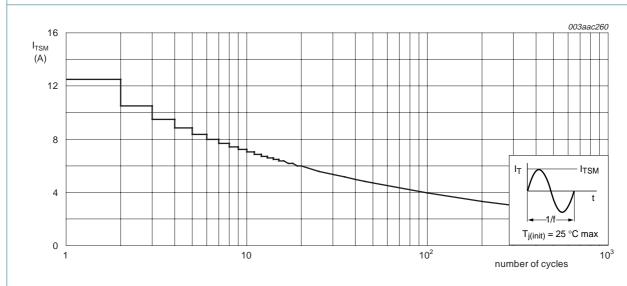
Symbol	Parameter	Conditions	Min	Max	Unit
V_{DRM}	repetitive peak off-state voltage		-	800	V
V_{RRM}	repetitive peak reverse voltage		-	800	V
I _{T(RMS)}	RMS on-state current	full sine wave; $T_{lead} \le 38$ °C; see Figure 4 and 5	-	1	Α
I _{TSM}	non-repetitive peak on-state current	full sine wave; $T_j = 25$ °C prior to surge; see Figure 2 and 3			
		t = 20 ms	-	12.5	Α
		t = 16.7 ms	-	13.8	Α
l ² t	I ² t for fusing	t _p = 10 ms	-	1.28	A ² s
dl _T /dt	rate of rise of on-state current	$I_{TM} = 1 \text{ A}; I_G = 20 \text{ mA};$ $dI_G/dt = 0.2 \text{ A}/\mu\text{s}$			
		T2+ G+	-	50	A/μs
		T2+ G-	-	50	A/μs
		T2- G-	-	50	A/μs
		T2- G+	-	10	A/μs
I_{GM}	peak gate current		-	1	Α
P_{GM}	peak gate power		-	2	W
$P_{G(AV)}$	average gate power	over any 20 ms period	-	0.1	W
T _{stg}	storage temperature		-40	+150	°C
T _j	junction temperature		-	125	°C

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 α = conduction angle

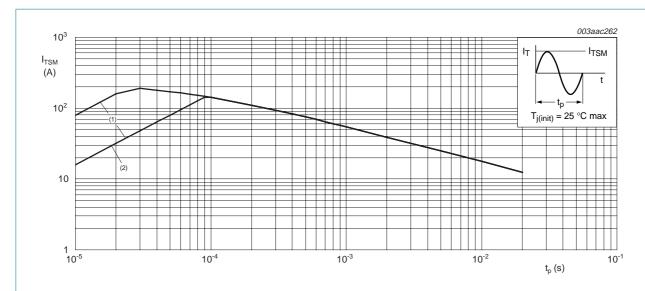
Fig 1. Total power dissipation as a function of RMS on-state current; maximum values



f = 50 Hz

Fig 2. Non-repetitive peak on-state current as a function of the number of sinusoidal current cycles; maximum values

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 $t_p \le 20 \text{ ms}$

- (1) dI_T/dt limit
- (2) T2- G+ quadrant limit

Fig 3. Non-repetitive peak on-state current as a function of pulse width; maximum values

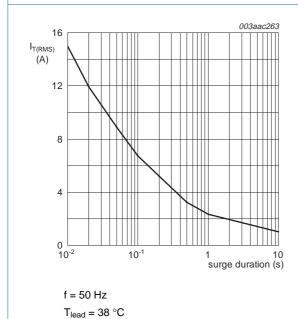


Fig 4. RMS on-state current as a function of surge duration; maximum values

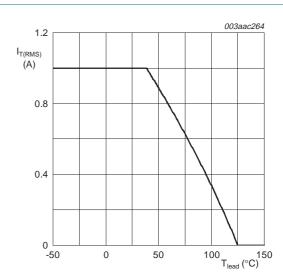


Fig 5. RMS on-state current as a function of solder point temperature; maximum values

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Thermal characteristics

Table 4. **Thermal characteristics**

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
$R_{\text{th(j-lead)}}$	thermal resistance from junction to lead	full cycle; see Figure 6	-	-	60	K/W
$R_{th(j-a)}$	thermal resistance from junction to ambient	full cycle; printed-circuit board mounted; lead length = 4 mm	-	150	-	K/W

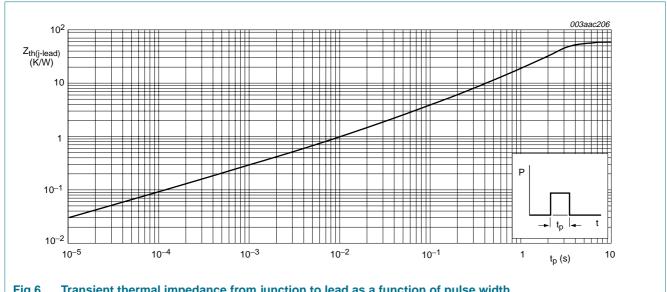


Fig 6. Transient thermal impedance from junction to lead as a function of pulse width

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6. Static characteristics

Table 5. Static characteristics

 $T_j = 25 \,^{\circ}C$ unless otherwise specified.

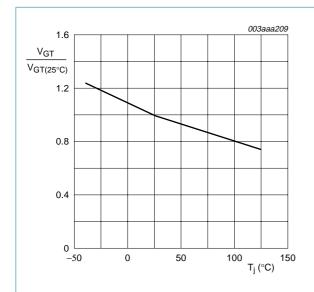
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
I_{GT}	gate trigger current	$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; see } \frac{\text{Figure 8}}{}$				
		T2+ G+	0.25	-	5	mA
		T2+ G-	0.25	-	5	mA
		T2- G-	0.25	-	5	mA
		T2- G+	0.35	-	7	mA
I _L latching current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; see } \frac{\text{Figure 10}}{\text{ of } 100000000000000000000000000000000000$					
		T2+ G+	-	-	10	mA
		T2+ G-	-	-	25	mA
		T2- G-	-	-	10	mA
		T2- G+	-	-	10	mA
I _H	holding current	$V_D = 12 \text{ V; } I_G = 0.1 \text{ A; see } \frac{\text{Figure 11}}{\text{Figure 11}}$	-	-	10	mA
V_{T}	on-state voltage	I _T = 1 A; see <u>Figure 9</u>	-	1.3	1.6	V
V _{GT} gate trigger voltage		$V_D = 12 \text{ V; } I_T = 0.1 \text{ A; see } \frac{\text{Figure 7}}{}$	-	-	1.3	V
		$V_D = V_{DRM}; I_T = 0.1 A; T_j = 125 ^{\circ}C$	0.2	-	-	V
I_D	off-state current	$V_D = V_{DRM(max)}$; $T_j = 125 ^{\circ}C$	-	-	0.5	mA

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7. Dynamic characteristics

Table 6. Dynamic characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
dV _D /dt	rate of rise of off-state voltage	$V_{DM} = 0.67 V_{DRM(max)}$; $T_j = 110$ °C; exponential waveform; gate open circuit	20	-	-	V/μs
dV _{com} /dt	rate of change of commutating voltage	$V_{DM} = 400 \text{ V}; T_j = 110 ^{\circ}\text{C}; I_{TM} = 1 \text{ A}; \\ dI_{com}/dt = 0.44 \text{ A/ms}$	1	-	-	V/μs



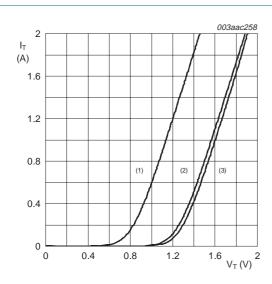
1GT | GT(25°C) | 3 | (1) | (2) | (3) | (4) | (4) | (4) | (4) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7) | (7)

- (1) T2+ G+
- (2) T2+ G-
- (3) T2- G-
- (4) T2-G+

Fig 7. Normalized gate trigger voltage as a function of junction temperature

Fig 8. Normalized gate trigger current as a function of junction temperature

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 $V_0 = 1.254 \text{ V}; R_s = 0.31 \Omega$

- (1) $T_j = 125 \,^{\circ}C$; typical values
- (2) $T_j = 125 \,^{\circ}C$; maximum values
- (3) $T_j = 25$ °C; maximum values

Fig 9. On-state current as a function of on-state voltage

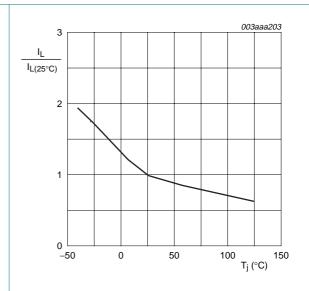


Fig 10. Normalized latching current as a function of junction temperature

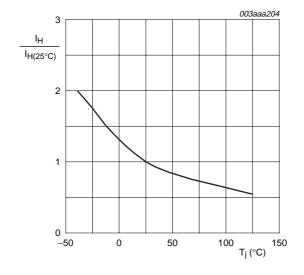


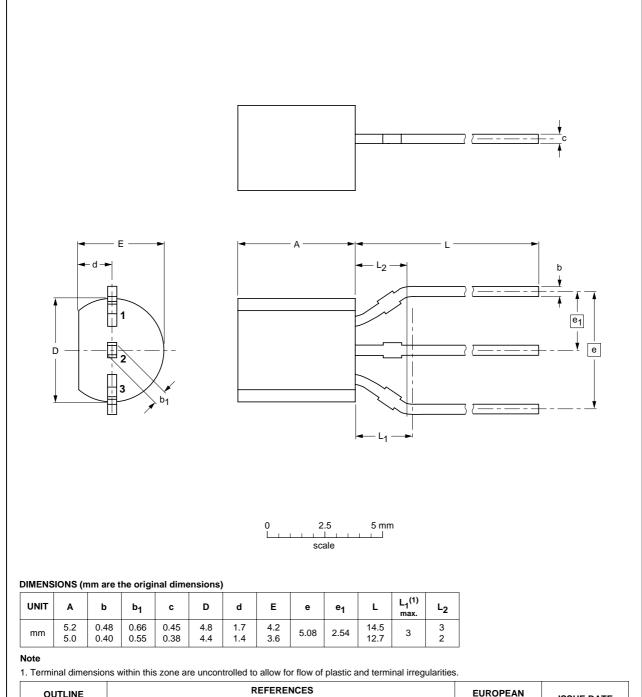
Fig 11. Normalized holding current as a function of junction temperature

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8. Package outline

Plastic single-ended leaded (through hole) package; 3 leads (wide pitch)

SOT54A



OUTLINE		REFER	RENCES	EUROPEAN	ISSUE DATE	
VERSION	IEC	JEDEC	JEITA	PROJECTION	ISSUE DATE	
SOT54A					97-05-13 04-06-28	

Fig 12. Package outline SOT54A

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9. Revision history

Table 7. Revision history

Document ID	Release date	Data sheet status	Change notice	Supersedes
OT407_1	20080519	Product data sheet	-	-

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10. Legal information

10.1 Data sheet status

Document status[1][2]	Product status[3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

- [1] Please consult the most recently issued document before initiating or completing a design.
- [2] The term 'short data sheet' is explained in section "Definitions"
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